Supporting Information

Growth modulation of nonlayered 2D-MnTe and MnTe/WS₂ heterojunction for high-performance photodetector

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Figure S1. Schematic diagram of the process to transfer MnTe nanosheets onto a copper mesh.



Figure S2. Low-magnification transmission electron microscopy images (a) and high-angle annular dark-field (HAADF) image (b) of MnTe nanosheet.



Figure S3. The average thickness of MnTe nanosheets grown at different gas flows.



Figure S4. Morphological evolution of MnTe nanosheets as single-domain net growth rate increases.



Figure S5. The optical microscopy image (a) and the AFM image (b) of MnTe-based FET device.



Figure S6. $I_{ds}\mbox{-}V_{ds}$ output characteristics of MnTe-based FET.



Figure S7. (a)PL spectra of MnTe nanosheets with different thicknesses. (b) PL spectra of a few layers of WS₂ nanosheets and MnTe/WS₂ heterostructure.



Figure S8. The optical microscopy image (a) and the AFM image (b) of $MnTe-WS_2$ heterojunction photodetector device.



Figure S9. Schematic diagram of the process to fabricate the MnTe/WS₂ photodetector.



Figure S10. Band alignment of MnTe/WS2 heterojunction.



Figure S11. The mechanism diagram of $MnTe-WS_2$ heterojunction photodetector.



Figure S12. The fitted curve of power density vs. photocurrent.

Materials	Method	Wavelengt	Photoresponsivit	Detectivit	Referenc
		h (nm)	y (A W ⁻¹)	y (Jones)	e
MnTe/WS ₂	CVD-restacking	637	0.271	1.23×10 ¹⁰	This
					work
WS ₂ /MoS ₂	CVD	532	0.00436	4.36×10 ¹³	1
WSe ₂ /SnS ₂	CVD	520	0.108	4.71×10 ¹⁰	2
GaSe/MoS ₂	CVD	300	0.065	-	3
GaSe/MoSe ₂	CVD	white light	0.03	-	4
SnS ₂ /MoS ₂	CVD	638	1.36	-	5
GaSe/Gasb	MBE	637	0.1	2.2×10 ¹²	6
ReS ₂ /ReSe ₂	Exfoliated-restacking	550	0.021	-	7
MoTe ₂ /MoS ₂	Exfoliated-restacking	473	0.06	1.60×10 ¹⁰	8
BP/InSe	Exfoliated-restacking	455	0.017	-	9

Table S1. Comparison of the photodetector performance with other 2D heterostructures.

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